

IGBT Chip in NPT-technology

FEATURES:

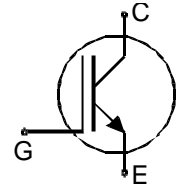
- 1200V NPT technology
- 200µm chip
- positive temperature coefficient
- easy paralleling

This chip is used for:

- BUP 213

Applications:

- drives



Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC25T120C	1200V	15A	5.71 x 4.53 mm ²	sawn on foil	C67078-A4674-A001

MECHANICAL PARAMETER:

Raster size	5.71 x 4.53	mm ²
Emitter pad size	2 x (2.18 x 1.6)	
Gate pad size	1.09 x 0.68	
Area total / active	25.9 / 18.7	
Thickness	180	µm
Wafer size	150	mm
Flat position	270	grd
Max.possible chips per wafer	555 pcs	
Passivation frontside	Photoimide	
Emitter metallization	3200 nm Al Si 1%	
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding	
Die bond	electrically conductive glue or solder	
Wire bond	Al, <500µm	
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm	
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C	

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_j=25\text{ °C}$	V_{CE}	1200	V
DC collector current, limited by T_{jmax}	I_C	¹⁾	A
Pulsed collector current, t_p limited by T_{jmax}	I_{cpuls}	45	A
Gate emitter voltage	V_{GE}	± 20	V
Operating junction and storage temperature	T_j, T_{stg}	-55 ... +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), $T_j=25\text{ °C}$, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=1mA$	1200			V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=15A$	2.0	2.5	3.0	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=0.6mA, V_{GE}=V_{CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200V, V_{GE}=0V$			1.9	μA
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=20V$			480	nA

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Input capacitance	C_{iss}	$V_{CE}=25V,$ $V_{GE}=0V,$ $f=1MHz$	-	1000	-	pF
Output capacitance	C_{oss}		-	150	-	
Reverse transfer capacitance	C_{rss}		-	70	-	

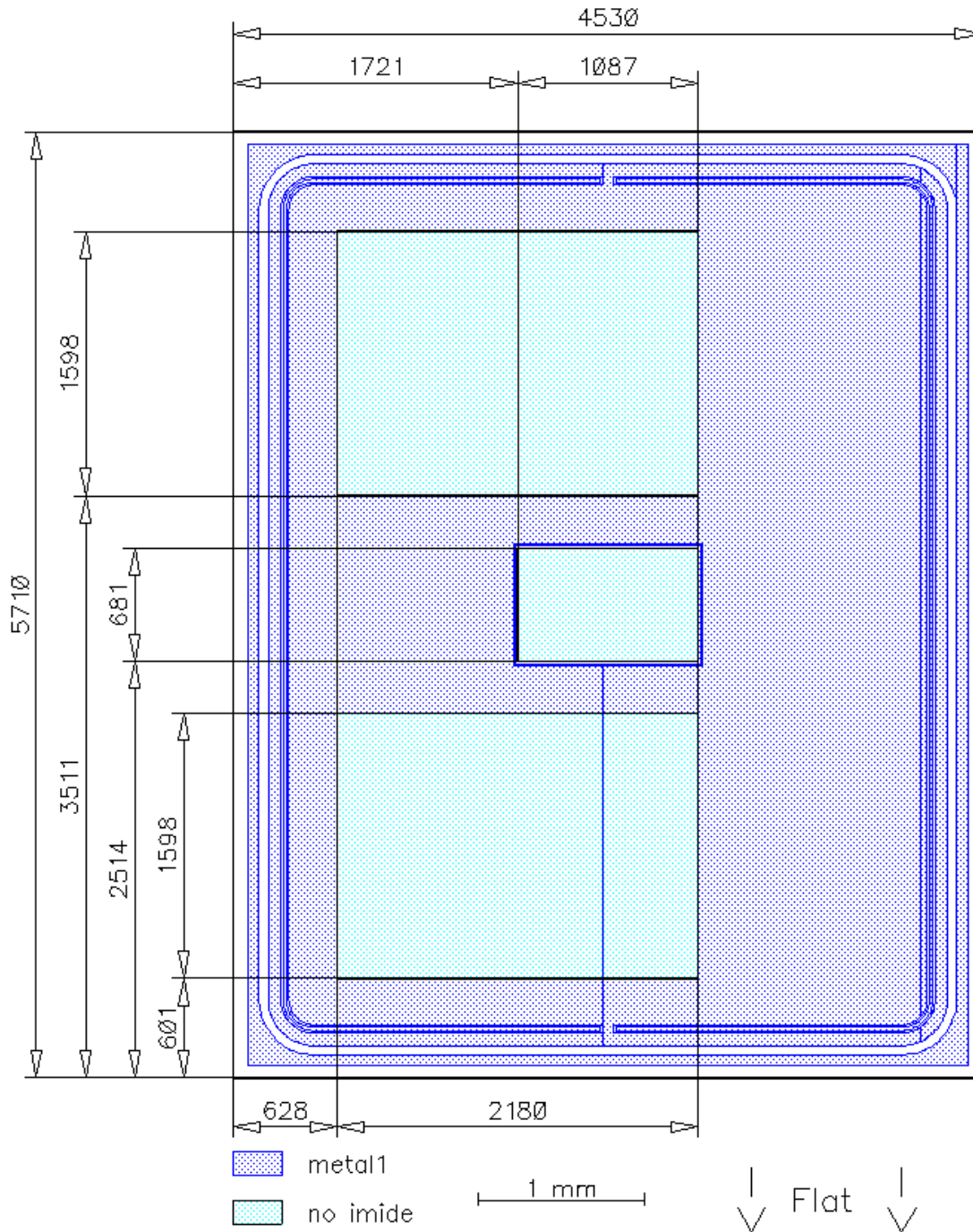
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions ¹⁾	Value			Unit
			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	$T_j=125\text{ °C}$ $V_{CC}=600V,$ $I_C=15A,$ $V_{GE}=+15/-15V,$ $R_G=82\Omega$	-	55		ns
Rise time	t_r		-	45		
Turn-off delay time	$t_{d(off)}$		-	400		
Fall time	t_f		-	70		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.

CHIP DRAWING:

Die-Size 4530 μm x 5710 μm



FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet	BUP213	Package TO220
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DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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